



FFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Quevedo-Lopez et al.

Art Unit: 2822

Serial No.: 10/726,987

Examiner: Thomas, T.

Filing Date: 12/03/2003

Docket No.: TI-36376

Customer No.: 23494

Conf. No.: 5051

Title: TOP SURFACE ROUGHNESS REDUCTION OF HIGH-k DIELECTRIC
MATERIALS USING PLASMA BASED PROCESSES

ELECTION

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

MAILING CERTIFICATE UNDER 37 C.F.R. § 1.8(A)
I hereby certify that the above correspondence is being deposited
with the U.S. Postal Service as first Class Mail in an envelope
addressed to Commissioner for Patents, PO Box 1450,
Alexandria, VA 22313-1450.

1-27-05
Date
Marianna Smith
Marianna Smith

Dear Sir:

With respect to the Restriction Requirement mailed on 01/04/2005, the Examiner has restricted the instant application to the invention of Group I (Claims 1-25), or Group II (Claims 26-31). In light of this, Applicants elect to pursue Group I, (Claims 1-25) without traverse.

The Examiner restricted the instant application to Species I – VII. Applicants elect to pursue Species VII with claims 5, 7, 9, and 10 readable thereon. Claims 1-3 and 11-25 are generic.

Respectfully submitted,

JJ Garner
Jacqueline J. Garner
Attorney for Applicants
Reg. No. 36,144

Texas Instruments Incorporated
P.O. Box 655474, M/S 3999
Dallas, TX 75265
(214) 532-9348 or
(972) 917-5643
Fax: (972) 917-4418